


<b>Search Notes</b> 	<b>Application/Control No.</b> 10087699	<b>Applicant(s)/Patent Under Reexamination</b> CHENG ET AL.
	<b>Examiner</b> David M Naff	<b>Art Unit</b> 1657

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
West-see search history	5/22/08	DMN
West-see search history	10/21/08	DMN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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